

Notice of References Cited	Application/Control No. 10/764,816	Applicant(s)/Patent Under Reexamination WU ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,130,882 A	10-2000	Levin, Howard E.	370/252
*	B	US-6,263,048 B1	07-2001	Nelson et al.	379/27.03
*	C	US-6,445,773 B1	09-2002	Liang et al.	379/1.04
*	D	US-6,498,808 B1	12-2002	Tzannes, Marcos	375/225
*	E	US-2003/0007455 A1	01-2003	Kohzuki et al.	370/230.1
*	F	US-2003/0033262 A1	02-2003	Aoki, Yasutaka	705/412
*	G	US-2003/0095591 A1	05-2003	Rekai et al.	375/225
*	H	US-2003/0189977 A1	10-2003	Sweitzer et al.	375/222
*	I	US-6,678,245 B1	01-2004	Cooper et al.	370/230
*	J	US-2005/0068891 A1	03-2005	Arsikere et al.	370/232
*	K	US-2005/0172030 A1	08-2005	Fay, Laurent	709/234
*	L	US-6,985,444 B1	01-2006	Rosen, Joseph S.	370/241
*	M	US-7,218,645 B2	05-2007	Lotter et al.	370/469

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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